and supplementary material) required for a short structural paper in *Acta Crystallographica* including the text. It is designed not only for giving structural data, but it can also include data as different as powder patterns and protein derivative structure factors.

Copies of the latest standard can be obtained from: Dr I. D. Brown, Institute for Materials Research, McMaster University, Hamilton, Ontario, Canada L8S 4M1. 1002332@mcmaster.netnorth

It is available in either hardcopy form or as a machine-readable file which may be sent over the NetNorth/Bitnet/Earn networks. A user-adaptable program to read an SCFS-87 file is available by network from: Dr H. D. Flack, Laboratoire de Cristallographie, Université de Genève, 24 quai Ernest-Ansermet, 1211 Genève 4, Switzerland. "flack@cgeuge52"

New Commercial Products

Announcements of new commercial products are published by the Journal of Applied Crystallography *free of charge. The descriptions, up to* 300 *words or the equivalent if a figure is included, should give the price and the manufacturer's full address. Full or partial inclusion is subject to the Editor's approval and to the space available. All correspondence should be sent to the Editor, Professor M. Schlenker, Editor* Journal of Applied Crystallography, *Laboratoire Louis Néel du CNRS, BP*166, *F*-38042 *Grenoble CEDEX, France.*

The International Union of Crystallography can assume no responsibility for the accuracy of the claims made. A copy of the version sent to the printer is sent to the company concerned.

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PL6100 Fourier Transform Photoluminescence Spectrometer

Photoluminescence spectroscopy is a well established technique for the characterization of impurities, crystal defects and dopants, such as the simultaneous assessment of both boron and phosphorus in silicon. Until recently, the conventional method for these measurements has been based on dispersive optical technology using a monochromator. These systems suffer from restricted sensitivity and long measurement times.

Fourier transform spectroscopy has been used intermittently for more than 20 years for photoluminescence measurement and its advantages are well known. Now the development of a high performance low-cost near-infrared Fourier transform spectrometer by Bio-Rad has led to the PL6100, a state of the art, high-sensitivity system.

The **PL6100 Fourier Transform Photoluminescence Spectrometer** illuminates the samples, which are mounted in a liquid-helium cryostat, with an argon ion laser. The optical performance of the system is such that greater than 15000 times signal-to-noise improvement is obtained over conventional systems using a monochromator enabling very weak spectral features to be observed. In addition, the use of a Fourier transform spectrometer enables measurement times to be reduced to typically 120 times less than with conventional equipment.

The software for the PL6100 is full menu-driven with a HELP key to guide the user.

*Bio-Rad MicroScience, 53–63 Greenhill Crescent, Watford Business Park, Watford, Herts WD*1 8*QS, England*

Books Received

The following book has been received by the Editor. Brief and generally uncritical notices are given of works of marginal crystallographic interest; occasionally a book of fundamental interest is included under this heading because of difficulty in finding a suitable reviewer without great delay.

J. Appl. Cryst. (1987). **20**, 538

Defect crystal chemistry and its applications. By R. J. D. Tilley. Pp. viii + 236. Glasgow and London: Blackie; USA: Chapman & Hall, 1987. Price £35.00. A review of this book, by A. A. Urusovskaya. has been published in the November 1987 issue of *Acta Crystallographica* Section A, page 840.